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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/789,997	SEKI ET AL.	
Examiner	Art Unit	
Hai C. Pham	2861	

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Class	Subclass	Date	Examiner
347	234-235, 248-250	8/4/2006	НР

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
347	249	8/4/2006	HP
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PGPub Te	ext Search	8/4/2006	НР

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	DATE	EXMR
EAST Text Search	8/4/2006	НР